



HIGH EFFICIENCY HETEROJUNCTION POWER FET CHIP (.25µm x 300µm)

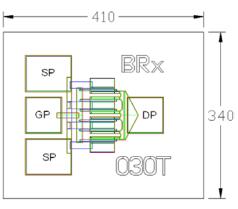
The BeRex BCP030T is a GaAs Power pHEMT with a nominal 0.25 micron gate length and 300 micron gate width making the product ideally suited for amplifier applications where high-gain and medium power from DC to 26 GHz. The product may be used in either wideband or narrow-band applications. The BCP030T is produced using state of the art metallization with SI₃N₄ passivation and is screened to assure reliability.

PRODUCT FEATURES

- 25 dBm Typical Output Power
- 14 dB Typical Gain @12 GHz
- 65% PAE Typical @12 GHz
- 0.25 X 300 µm Recessed Gate
- Also available in 70 mil. ceramic package (BCP030T-70)

APPLICATIONS

- Commercial
- Military / Hi-Rel.
- Test & Measurement



Chip dimensions : 410 X 340 microns Gate pad(GP) : 75 X 75 microns Drain pad(DP) : 75 X 75 microns Source pad(SP) : 95 X 75 microns Chip thickness : 100 microns

DC CHARACTERISTICS T_a = 25° C

SYMBOL	PARAMETER/TEST CONDITIONS	MIN.	TYPICAL	MAX.	UNIT
I _{dss}	Saturated Drain Current ($V_{gs} = 0V$, $V_{ds} = 1.0V$)	60	90	120	mA
Gm	Transconductance (V_{ds} = 2V, Vgs = 50% I_{dss})		120		mS
Vp	Pinch-off Voltage (I_{ds} = 0.3 mA, V_{ds} = 2V)	-2.5	-1.1	-0.5	V
BV_{gd}	Drain Breakdown Voltage (Ig = 0.3 mA, source open)		-15	-12	V
BV_{gs}	Source Breakdown Voltage (Ig = 0.3 mA, drain open)		-13		V
Rth	Thermal Resistance (Au-Sn Eutectic Attach)		121		°C/W

ELECTRICAL CHARACTERISTICS (TUNED FOR POWER) T_a = 25° C

SYMBOL	PARAMETER/TEST CONDITIONS	TEST FREQ.	MIN.	TYPICAL	MAX.	UNIT
P _{1dB}	Output Power @ P _{1dB} (V _{ds} = 8V, I _{ds} = 50% I _{dss})	12 GHz	24.5	25.5		dBm
		18 GHz		25.5		
6	Gain @ P_{1dB} ($V_{ds} = 8V$, $I_{ds} = 50\% I_{dss}$)	12 GHz	13.0	14.0		dB
G _{1dB}		18 GHz		10.5		ив
PAE	PAE @ P _{1dB} (V _{ds} = 8V, I _{ds} = 50% I _{dss})	12 GHz		65		%
PAL		18 GHz		60		
NF	50 Ohm Noise Figure (V _{ds} =2V, I _{ds} =15 mA)	12 GHz		1.14		dB

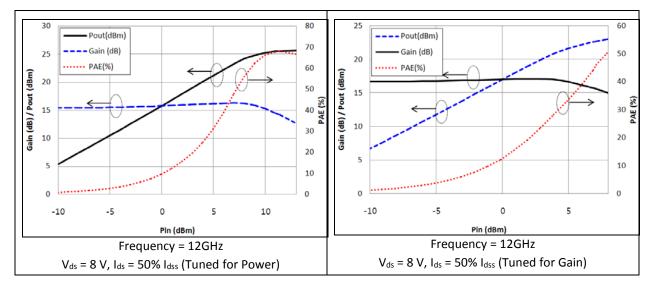
SYMBOL	PARAMETER/TEST CONDITIONS	TEST FREQ.	MIN.	TYPICAL	MAX.	UNIT
P _{1dB}	Output Power @ P _{1dB} (V _{ds} = 8V, I _{ds} = 50% I _{dss})	12 GHz	22.0	23.0		dBm
		18 GHz		23.0		
G _{1dB}	Gain @ P1dB (Vds = 8V, Ids = 50% Idss)	12 GHz	14.5	15.5		dB
Glab		18 GHz		11.5		uв
PAE	PAE @ P _{1dB} (V _{ds} = 8V, I _{ds} = 50% I _{dss})	12 GHz		45		%
FAL		18 GHz		45		/0
NF	50 Ohm Noise Figure (V_{ds} =2V, I_{ds} =15 mA)	12 GHz		1.14		dB

ELECTRICAL CHARACTERISTICS (TUNED FOR GAIN) $T_a = 25^{\circ} C$

MAXIMUM RATINGS (T_a = 25° C)

SYMBOLS	PARAMETERS	ABSOLUTE	CONTINUOUS	
Vds	Drain-Source Voltage	12 V	8 V	
Vgs	Gate-Source Voltage	-6 V	-3 V	
l _{ds}	Drain Current	l _{dss}	ldss	
l _{gsf}	Forward Gate Current	18 mA	3 mA	
Pin	Input Power	22 dBm	@ 3dB compression	
T_{ch}	Channel Temperature	175° C	150° C	
T_{stg}	Storage Temperature	-60° C - 150° C	-60° C - 150° C	
Pt	Total Power Dissipation	1.4 W	1.2 W	

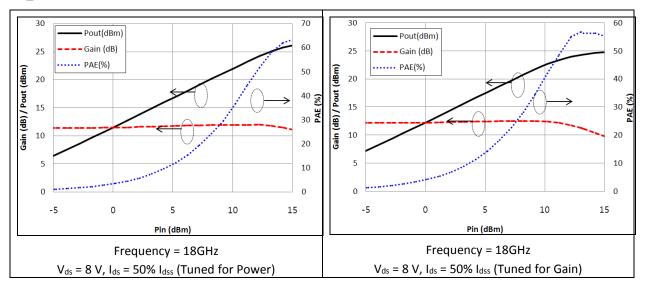
Exceeding any of the above Maximum Ratings will result in reduced MTTF and may cause permanent damage to the device.



PIN_POUT/GAIN, PAE (12 GHz)

BCP030T

PIN_POUT/GAIN, PAE (18 GHz)



S-PARAMETER (V_{ds} = 8V, I_{ds} = 50% I_{dss})

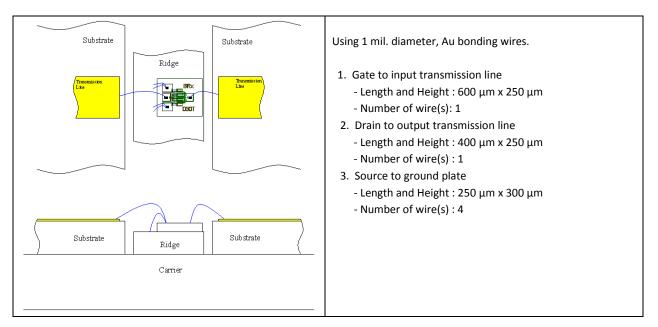
FREQ.	S11	S11	S21	S21	S12	S12	S22	S22
[GHZ]	[MAG]	[ANG.]	[MAG]	[ANG.]	[MAG]	[ANG.]	[MAG]	[ANG.]
1	0.97	-27.72	9.10	159.71	0.019	74.59	0.71	-10.54
2	0.91	-53.85	8.41	141.85	0.036	61.30	0.66	-19.37
3	0.85	-78.65	7.57	126.23	0.048	50.31	0.59	-26.23
4	0.79	-100.97	6.73	112.12	0.055	41.94	0.54	-32.00
5	0.75	-121.90	5.95	99.32	0.061	35.64	0.48	-37.41
6	0.73	-139.47	5.24	88.30	0.062	30.97	0.44	-41.98
7	0.72	-155.99	4.62	77.67	0.062	24.97	0.40	-48.43
8	0.72	-168.99	4.14	68.95	0.063	21.67	0.38	-51.15
9	0.72	-179.97	3.71	61.22	0.060	19.65	0.36	-54.78
10	0.72	169.20	3.37	53.50	0.060	18.02	0.34	-58.30
11	0.74	160.38	3.04	46.46	0.060	16.99	0.33	-60.45
12	0.75	151.34	2.81	39.07	0.059	13.84	0.32	-63.94
13	0.76	142.18	2.58	32.32	0.059	14.91	0.30	-65.39
14	0.79	135.08	2.37	25.60	0.059	12.56	0.28	-67.17
15	0.80	128.26	2.21	19.05	0.060	12.24	0.25	-70.97
16	0.82	120.51	2.05	12.14	0.061	10.92	0.21	-75.16
17	0.85	116.46	1.88	5.62	0.060	8.30	0.17	-84.42
18	0.86	110.04	1.73	-1.49	0.064	5.45	0.13	-99.08
19	0.88	104.87	1.57	-9.16	0.065	3.39	0.10	-131.69
20	0.89	103.82	1.43	-14.39	0.066	3.64	0.11	-175.84
21	0.90	100.91	1.30	-20.35	0.069	1.83	0.17	160.35
22	0.90	99.40	1.15	-25.89	0.068	1.36	0.24	149.32
23	0.90	100.87	1.04	-30.07	0.067	-0.48	0.31	142.60
24	0.90	98.38	0.93	-34.99	0.066	-1.84	0.39	139.62
25	0.92	99.27	0.83	-38.62	0.068	-0.48	0.45	137.44
26	0.92	101.85	0.76	-40.47	0.064	4.76	0.49	137.87

Note: S-parameters include bond wires. Reference planes are at edge of substrates shown on "Wire Bonding Information" figure below.

BeRex, Inc. 3350 Scot Blvd. #61-01 Santa Clara, CA 95054 tel. (408) 452-5595 Specifications are subject to change without notice. ©BeRex 2015 Rev. 1.7

WIRE BONDING INFORMATION

Follow the wire bonding diagrams recommended by BeRex below to achieve optimum device performance. BeRex recommends thermo-compression wedge bonding. As a general rule, bonding temperature should be kept to a maximum of 280°C for no longer than 2 minutes for all bonding wires. Ultrasonic bonding is not recommended.





Proper ESD procedures should be followed when handling this device.

DIE ATTACH RECOMMENDATIONS:

BeRex recommends the "Eutectic" die attach using Au-Sn (80%-20%) pre-forms. The die attach station must have accurate temperature control, and the operation should be performed with parts no hotter than 300°C for less than 10 seconds. An inert forming gas (90% N₂-10% H₂) or clean, dry N₂ should be used.

Use of conductive epoxy (gold or silver filled) may also be acceptable for die-attaching low power devices.

HANDLING PRECAUTIONS:

GaAs FETs are very sensitive to and may be damaged by Electrostatic Discharge (ESD). Therefore, proper ESD precautions must be taken whenever you are handling these devices. It is critically important that all work surfaces, and assembly equipment, as well as the operator be properly grounded when handling these devices to prevent ESD damage.

STORAGE & SHIPPING:

BeRex's standard chip device shipping package consists of an antistatic "Gel-Pak", holding the chips, placed inside a sealed antistatic and moisture barrier bag. This packaging is designed to provide a reasonable measure of protection from both mechanical and ESD damage.

Chip devices should be stored in a clean, dry Nitrogen gas environment at room temperature until they are required for assembly. Only open the shipping package or perform die assembly in a work area with a class 10,000 or better clean room environment to prevent contamination of the exposed devices.

CAUTION:

THIS PRODUCT CONTAINS GALLIUM ARSENIDE (GaAs) WHICH CAN BE HAZARDOUS TO THE HUMAN BODY AND THE ENVIRONMENT. THEREFORE, IT MUST BE HANDLED WITH CARE AND IN ACCORDANCE WITH ALL GOVERNMENTAL AND COMPANY REGULATIONS FOR THE SAFE HANDLING AND DISPOSAL OF HAZARDOUS WASTE. DO NOT BURN, DESTROY, CUT, CRUSH OR CHEMICALLY DISSOLVE THE PRODUCT. DO NOT LICK THE PRODUCT OR IN ANY WAY ALLOW IT TO ENTER THE MOUTH. EXCLUDE THE PRODUCT FROM GENERAL INDUSTRIAL WASTE OR GARBAGE AND DISPOSE OF ONLY IN ACCORDANCE TO APPLICABLE LAWS AND/OR ORDINANCES

DISCLAIMER

BEREX RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. BEREX DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN.

LIFE SUPPORT POLICY

BEREX PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES WITHOUT THE EXPRESS WRITTEN APPROVAL OF BEREX.

- Life support devices or systems are devices or systems which (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in labeling, can be reasonably expected to result in significant injury to the user.
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

For complete specifications, S-parameters and information on bonding and handling,

visited our website; www.berex.com

3.